

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4870561	die\$1 or "IC"\$1 or integrated\$1circuit\$1 or (integrated adj circuit\$1) or chip\$1 or semiconductor or ic\$1chip\$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/03 20:58
L2	14274	((438/14) or (438/17) or (438/18) or (438/106) or (438/110) or (438/113) or (257/E21.521) or (257/E21.522) or (257/E21.524) or (257/E21.525) or (257/E21.529)).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/03 20:58
L3	4869108	die\$1 or "IC"\$1 or integrated\$1circuit\$1 or (integrated adj circuit\$1) or chip\$1 or semiconductor or ic\$1chip\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/03 20:58
L4	12765	L2 and L3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/03 20:58
L5	3582	(test\$3 or (failure with analysis)) with (wafer\$1level or (wafer adj level))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/03 20:59
L6	393	4 and 5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/03 20:59